

Form PTO 1449
(Modified)U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICEATTY DOCKET NO.
243329US2SERIAL NO.
New Application

LIST OF REFERENCES CITED BY APPLICANT

APPLICANT
Kenichi KADOTAFILING DATE
Herewith

GROUP

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	AA						
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
	AL						
	AM						
	AN						

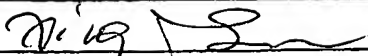
FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION	
					YES	NO
XS	AO	2002-323924	11/08/02	Japan (with English Abstract)		x
	AP					
	AQ					
	AR					
	AS					
	AT					
	AU					
	AV					

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)

XS	AW	Laura PETERS, "Graphically Analyzing Yield Loss", SEMICONDUCTOR INTERNATIONAL, October 1999, page 54				
	AX					
	AY					
	AZ				<input type="checkbox"/> Additional References sheet(s) attached	

Examiner



Date Considered

02/21/06

*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.